

# Evaluating the Durability of Balance of Systems Components Using C-AST

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DuraMAT Webinar, Monday, 2021/11/08

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# The Motivation for the BoS Study

- BoS components include: connectors, cables, **branch connectors**, fuses (discrete), fuse blocks.
- Durability of BoS components has very limited research examination.
- Quantifiable replacement rate for t < 25y! 50y: TBD. -2 DOE AOP projects presently examining: components, occurrence, cost. Example of PV fires in Italy.
- Consequences of degradation and failure: module offline, string offline, tripped inverter, system shutdown, arc fault, fire!!!

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• With limited publicity, latter consequences are BoS-centric.



Fiorentini et. al., PVRW 2020.



## Goals of the C-AST Project

#### General:

- C-AST typically used with MiMos, so:
	- -Develop characterization methods.
	- -Identify degradation modes.
	- -Demonstrate ability to distinguish known bad components using C-AST.

### Specific:

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- -Identify most damaging stressors (environments, from C-AST sequences).
- -Can static load or mechanical vibration contribute to failure?



C-AST chamber during operation (MiMo test sites).

## Look For in This Presentation

*-External mechanical actuation greatly affected the result.-*

• How is examination implemented?

• What component(s) are affected?

• How to further validate the result?





### Branch Connectors: The Scenario







• Utility provider experiencing ~30% failure rate in their power transfer chain, attributed to branch connectors. -"Failure" means overheating, softening, physical distortion. -Observable ∆T in thermographic imaging.

-Worst consequence: broken circuit, arc, fire.

• Component makes & models kept confidential in this presentation.





### Branch Connectors: The Approach





- Compare **C-AST** to UL standard tests.
- # and contribution of bad components unknown.

Evaluate proximate system components: cable connectors, fuse, branch connectors.

- **Develop fixture and software using benchtop experiments (1 replicate).**
- Use custom C-AST fixture for mechanical actuation (6 replicates).





### A Benchtop, Sample Integrated Push/Pull Mechanical Fixture Was Used

- "Yoke and push-rod" concept design concept was selected. (vs. "wedge").
- Specimen assembly is part of the actuation mechanism.
- Deflection used: 3 mm (initial)  $\rightarrow$  1 mm  $\rightarrow$  0.5 mm (C-AST).
- Benchtop version run with 16 rpm DC motor.
- C-AST version uses hydraulic actuators, 1/8 10 Hz.



## Mechanical Actuation Readily Affected Test Results



Static (unactuated) assembly

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#### Operation:

- Start at 10 A / 20 A applied DC current.
	- Current incremented 1 A each day to failure.

#### Observed limits:

- Static assembly: fails at 35 A (equiv. labels for 30 A).
- Dynamic assembly: fails at 15 A.  $T_{\text{external}}$  > 130°C.
- UL connector test: no failure BC  $\omega$  37.5 A. T<sub>external</sub> 44°C.

#### Failure modes:

- Static assembly: fails at fuse (open circuit).
- Dynamic assembly: fails at fuse/branch.

-Local arcing suspected from: smoke, local melting of plastic, discolored metal pins, increased fuse resistance.

## I-V: Mechanical Actuation Gave an Immediate, On-going Affect

- LabView software for C-AST developed in benchtop experiments.
- I, V are logged per sample assembly.
- Data binned & analyzed in 1 minute intervals.
- Optional "burst" mode to log @ 100 kHz.

- Example ( $\delta$ =1 mm) compares I, V for static & dynamic assemblies.
- -I, V scales (y-axis) are different, static vs. dynamic.
- -V quickly becomes more variable for dynamic.

- Foldback protection (>  $V_{fb}$ ) was extended from 1 to 5 to 25 s.  $\begin{bmatrix} 0.5 \\ 0.6 \end{bmatrix}$
- Q: what would you use to simulate an inverter?





## T: Mechanical Actuation Gave an Immediate, On-going Affect

• T is logged per site (F/MM BC, fuse 1, fuse 2, M/FF BC). -Discrete T-type thermocouples in sheet package.



• Example ( $\delta$ =1 mm) compares T for static & dynamic assemblies. -Scale (y-axis) same for static & dynamic. -FLIR vs. TC: exact hottest spot difficult to predict. -Helpful to know:  $t_{onset}$ , what components affected.



Data from experiment 4. Red arrows indicate approximate read point for FLIR imaging.

### DSC & FTIR Identify Connector Ends Are Polycarbonate

Q: What is the phase transition temperature, what material is implied for black deformed plastic?  $\Box$  $\rightarrow$ DSC and FTIR examination of unaged samples.

•Suspect hard structural polymer (PC, ABS, etc) from handling samples. • $T_{glass}$  of 142 $\pm$ 5°C (AVG  $\pm$  2 S.D.) suggests material is amorphous PC. •All samples gave similar response (scans from -90 − 200 °C), including: Suspect hard structural polymer (PC, ABS, etc) from handling samples.<br>  $T_{glass}$  of 142±5°C (AVG ± 2 S.D.) suggests material is amorphous PC.<br>
All samples gave similar response (scans from -90 – 200 °C), including:<br>
cable co



DSC for cable connector, female end (plastic).

•Cable-, branch-, fuse- connectors have same FTIR spectra. -Similar to polycarbonate reference sample. -2 measurements from separate pieces each component. -FTIR spectra verified on both F and M connector ends.

⇒Suspect PC containing carbon black.



FTIR (left) for all component ends and (right) PC reference.

#### XCT: Different Sample Locations, Temperatures May Dominate Between Field & "C-AST"

- •Figures: X-ray Computed Tomography imaging of field- and accelerated tested-samples.
- •Field samples show asymmetry not present on unaged samples.
- •Accelerated samples: bulge + contrast proximate to solder.

- •Convolute spring component shape unchanged.
	- T<sub>forge</sub> Cu ~900°C. T<sub>melt</sub> Cu 1085°C.
- Aluminum bronze fuse holder shape unchanged.
- $-T_{\text{softening}}$ Al/Cu ~315°C.  $T_{\text{melt}}$ Al/Cu >550°C. •Solder may contribute to failure.
	- $-T_{\text{molt}}$ Sn/Ag/?Cu? ~220°C.

plastic  $\Rightarrow$  142 °C realized in field. solder ⇒220 °C realized in accelerated test.





Unaged metal pins, utility provider<br>Metal pins, utility provider.





Unaged metal pins, utility provider.

Metal pins, benchtop  $\delta$  = 3 mm.

## The Destructive Failure Analysis Procedure Following XCT

1. Remove (mill) external plastic.

- -Retain plastic for F/A (FTIR, DSC).
- -Inspect internal metal components relative to XCT.

-Methods: camera, optical microscopy, SEM/EDX.

2. Extract (cut, unfold) convolute spring from F metal pins.

-Inspection, methods as above.



#### convolute spring, extracted from unaged metal pin



### Optical Micrscopy: Oxidation of Spring, with Mechanical Wear for  $\delta$  = 3 mm



Metal pins, benchtop  $\delta$  = 3 mm.

- Both: appearance (discolored, distorted) consistent with XCT.
- Discoloration suggests oxidation of convolute springs. (∆T).
	- -More localized discoloration in benchtop specimen.
- Scuff marks (ends, interior) suggest wear during accelerated test.

### **Present Status**

#### Branch Connectors:

- On-going failure analysis: solder vs. spring,  $\delta$  = 1 mm. -Do we still see wear?
- Static assembly branch connectors through round 1 of C-AST (10 A).
- Dynamic C-AST branch connector assembly pending. -Will effect of mechanical actuation be observed as in benchtop experiments? -Will effect of weathering be observed?
- May apply second round of C-AST (increased current).
- Final comparison at IEEE PVSC 2022.

## Remember From This Presentation

*-External mechanical actuation greatly affected the result.-*

- How is examination implemented? -*sample integrated push/pull mechanical fixture*
- What component(s) are affected? *-static: fuse (internal). -with actuation: BC/fuse (observed for field).*
- How to further validate the result?  $-mechanical wear observed for  $\delta$  = 3mm.$ *-pending C-AST @* δ *= 0.5mm.*



## Acknowledgements

#### Thanks to:

#### -DuraMAT management team.

Funding was provided as part of the Durable Modules Consortium (DuraMAT), an Energy Materials Network Consortium funded under Agreement 32509 by the U.S. Department of Energy (DOE), Office of Energy Efficiency & Renewable Energy, Solar Energy Technologies Office (EERE, SETO). This work was authored in part by the NREL, operated by Alliance for Sustainable Energy, LLC for the US DOE under contract no. DE-AC36-08GO28308. The views expressed in the presentation do not necessarily represent the views of the DOE or the U.S. government. Instruments and materials are identified in this paper to describe the experiments. In no case does such identification imply recommendation or endorsement by LBNL, NREL, SLAC, or SNL.

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#### The Please add to the "Questions and Answers" or contact: [David.Miller@nrel.gov](mailto:David.Miller@nrel.gov)

NREL/PR-5K00-81456